High-Current, High & Low-Side, Gate-Driver IC

Product Preview

FAN73912A

Description

The FAN73912A is a monolithic high and low-side gate-drive IC designed for high-voltage and high-speed driving for MOSFETs and IGBTs that operate up to +1200 V.

The advanced input filter of HIN provides protection against short-pulsed input signals caused by noise.

An advanced level-shift circuit offers high-side gate driver operation up to VS = -9.8 V (typical) for VBS = 15 V. The UVLO circuit prevents malfunction when VCC and VBS are lower than the specified threshold voltage.

Output drivers typically source and sink 2 A and 3 A, respectively.

- Floating Channel for Bootstrap Operation to +1200 V
- Typically 2 A/3 A Sourcing/Sinking Current Driving Capability for **Both Channels**
- Gate Driver Supply (VCC) Range from 12 V to 20 V
- Separate Logic Supply (VDD) Range from 3 V to 20 V
- Extended Allowable Negative VS Swing to -9.8 V for Signal Propagation at VCC = VBS = 15 V
- Built-in Cycle-by-Cycle Edge-Triggered Shutdown Logic
- Common-Mode dv/dt Noise Canceling Circuit
- UVLO Functions for Both Channels
- Built-in Advanced Input Filter
- Matched Propagation Delay Below 60 ns
- Outputs in-Phase with Input Signal
- Logic and Power Ground +/- 10 V Offset

Typical Application

- Electrical Contactor
- Industrial Motor Driver
- UPS
- Solar Inverter
- Ballast
- General-Purpose Half-Bridge Topology



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CASE 751BH

MARKING DIAGRAM



ORDERING INFORMATION

Device	Package	Shipping [†]
FAN73912AMX	Wide-16	1,000/
(Note 1)	SOIC	Tape & Reel

- †For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.
- 1. This device passed wave-soldering test by JESD22A-111

This document contains information on a product under development. ON Semiconductor reserves the right to change or discontinue this product without notice.

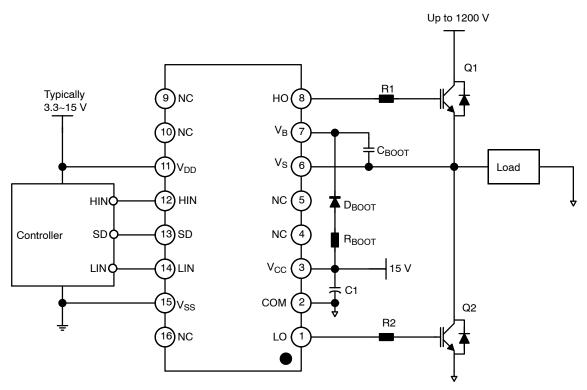


Figure 1. Application Schematic - Adjustable Option

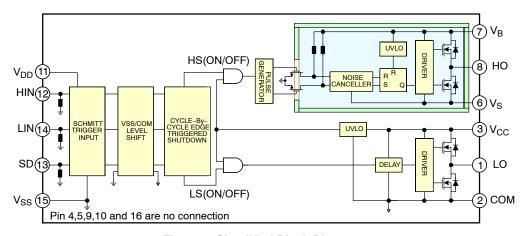


Figure 2. Simplified Block Diagram

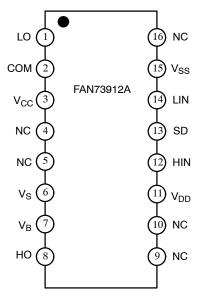


Figure 3. Pin Connections – Wide 16–SOIC (Top View)

Table 1. PIN FUNCTION DESCRIPTION (Note 2)

Pin No.	Symbol	Description
1	LO	Low-Side Driver Output
2	COM	Low-Side Driver Return
3	VCC	Low-Side Supply Voltage
4	NC	No Connection
5	NC	No Connection
6	V _S	High-Voltage Floating Supply Return
7	V _B	High-Side Floating Supply
8	НО	High-Side Driver Output
9	NC	No Connection
10	NC	No Connection
11	V_{DD}	Logic Supply Voltage
12	HIN	Logic Input for High-Side Gate Driver Output
13	SD	Logic Input for Shutdown
14	LIN	Logic Input for Low-Side Gate Driver Output
15	V _{SS}	Logic Ground
16	NC	No Connection

^{2.} Do not connect NC pins to ground or any other nodes in the circuitry to ensure floating status.

Table 2. MAXIMUM RATINGS (TA = 25°C, unless otherwise specified. All voltage parameters are referenced to COM unless otherwise stated in the table.)

Symbol	Parameter	Min	Max	Unit
V _B	High–Side Floating Supply Voltage $ T_J = 150^\circ C \\ T_J = 25^\circ C \\ T_J = -40^\circ C $	-0.3 -0.3 -0.3	1225.0 1225.0 1125.0	V
V _S	High-Side Floating Offset Voltage $ T_J = 150^{\circ}C \\ T_J = 25^{\circ}C \\ T_J = -40^{\circ}C $	V _B -25 V _B -25 V _B -23	V _B +0.3 V _B +0.3 V _B +0.3	V
V _{HO}	High-Side Floating Output Voltage	V _S -0.3	V _B +0.3	V
V _{CC}	Low-Side Supply Voltage	-0.3	25	V
V _{LO}	Low-Side Floating Output Voltage	-0.3	V _{CC} +.0.3	V
V _{DD}	Logic Supply Voltage	-0.3 V _{SS} -0.3	25 V _{SS} +25	V
V _{SS}	Logic GND	V _{DD} −25	V _{DD} +0.3	V
V _{IN}	Logic Input Voltage (HIN, LIN and SD)	-0.3 V _{SS} + V _{DD} -25.3	25 V _{DD} +0.3	V
dV _S /dt	Allowable Offset Voltage Slew Rate	-	±50	V/ns
P _D (Note 3, 4, 5)	Power Dissipation	-	1.3	W
$\theta_{\sf JA}$	Thermal Resistance	-	95	°C/W
T _J	Junction Temperature	-	150	°C
T _{STG}	Storage Temperature	-55	150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 3. Mounted on 76.2 x 114.3 x 1.6 mm PCB (FR-4 glass epoxy material).
- 4. Refer to the following standards:
 - JESD51-2: Integral circuit's thermal test method environmental conditions, natural convection;
 - JESD51-3: Low effective thermal conductivity test board for leaded surface-mount packages.
- 5. Do not exceed maximum power dissipation (\dot{P}_D) under any circumstances.

Table 3. RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Min	Max	Unit
V _B	High-Side Floating Supply Voltage	V _S + 12	V _S + 20	V
Vs	High-Side Floating Supply Offset Voltage (Note 6)	8 – V _{CC}	1200	V
V _{HO}	High-Side (HO) Output Voltage	V _S	V _B	V
V _{CC}	Low-Side Supply Voltage	12	20	V
V _{LO}	Low-Side (LO) Output Voltage	0	V _{CC}	V
V_{DD}	Logic Supply Voltage	V _{SS} + 3	V _{SS} + 20	V
V _{SS}	Logic Ground (Note 7)	-10	10	V
V _{IN}	Logic Input Voltage (HIN, LIN, SD)	0 V _{SS} + V _{DD} – 20	20 V _{DD}	V
T _A	Ambient Temperature	-40	+125	°C

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

- 6. Referenced to $T_J = 25^{\circ}C$. 7. When $V_{DD} < 10$ V, the minimum V_{SS} offset is limited to $-V_{DD}$.

Table 4. STATIC ELECTRICAL CHARACTERISTICS (V_{BIAS} (V_{CC} , V_{BS} , V_{DD}) = 15.0 V, T_J = -40°C to 125°C, unless otherwise specified. The V_{IH} , V_{IL} and I_{IN} parameters are referenced to V_{SS} and are applicable to respective input leads: HIN, LIN and SD. The V_O and I_O parameters are referenced to V_S and COM and are applicable to the respective output leads: HO and LO. The V_{DDUV} parameters are referenced to COM. The V_{BSUV} parameters are referenced to $V_{S1,\,2,\,3}$)

Symbol	Parameter	Con	ditions	Min	Тур	Max	Units	
LOW-SIDE	POWER SUPPLY SECTION	•			•			
I _{QCC}	Quiescent V _{CC} Supply Current	$V_{IN} = 0 \text{ V or } V_{DD}$ $T_J = 25^{\circ}\text{C}$		-	170	300	μΑ	
			$T_{J} = -40^{\circ}\text{C to } 125^{\circ}\text{C}$	-	170	350	1	
I _{QDD}	Quiescent V _{DD} Supply Current	$V_{IN} = 0 \text{ V or } V_{DD}$	T _J = 25°C	-	_	10	μΑ	
			$T_{J} = -40^{\circ}\text{C to } 125^{\circ}\text{C}$	-	-	20	1	
I _{PCC}	Operating V _{CC} Supply Current	f _{IN} = 20 kHz, rms V _{II}	_N = 15 V _{PP}	1	650	950	μΑ	
IPDD	Operating V _{DD} Supply Current	f _{IN} = 20 kHz, rms V _{II}	_N = 15 V _{PP}	-	2	-	1	
I _{SD}	Shutdown Supply Current	$S_D = V_{DD}$		-	30	50	μΑ	
V _{CCUV+}	V _{CC} Supply Under-Voltage Positive-Going Threshold Voltage	V _{CC} = Sweep		9.7	11.0	12	V	
V _{CCUV} -	V _{CC} Supply Under-Voltage Negative-Going Threshold Voltage	V _{CC} = Sweep		9.2	10.5	11.4	V	
V _{CCUVH}	V _{CC} Supply Under-Voltage Lockout Hysteresis Voltage	V _{CC} = Sweep		-	0.5	-	V	
300TSTRA	APPED SUPPLY SECTION							
I _{QBS}	Quiescent V _{BS} Supply Current	V _{IN} = 0 V or V _{DD}		-	50	100	μΑ	
I _{PBS}	Operating V _{BS} Supply Current	f _{IN} = 20 kHz, rms va	lue	-	550	850	μΑ	
V _{BSUV+}	V _{BS} Supply Under-Voltage Positive-Going Threshold Voltage	V _{BS} = Sweep		9.7	11.0	12.0	V	
V _{BSUV} -	V _{BS} Supply Under-Voltage Negative-Going Threshold Voltage	V _{BS} = Sweep		9.2	10.5	11.4	V	
V _{BSUVH}	V _{BS} Supply Under-Voltage Lockout Hysteresis Voltage	V _{BS} = Sweep		-	0.5	-	V	
I _{LK}	Offset Supply Leakage Current	V _B = V _S = 1200 V (T	_J = 25°C, 125°C)	-	-	100	μΑ	
		V _B = V _S = 1100 V (T	_J = -40°C)	-	-	100	1	
NPUT LOG	IC SECTION (HIN.LIN AND AD)							
V _{IH}	Logic "1" Input Voltage	V _{DD} = 3 V		2.4	_	_	V	
		V _{DD} = 15 V	T _J = 25°C	9.5	-	-		
			$T_J = -40^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	10.5	-	-		
V _{IL}	Logic "0" Input Voltage	V _{DD} = 3 V		-	-	0.8	V	
		V _{DD} = 15 V	T _J = 25°C	-	-	6.0		
			$T_J = -40^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	-	-	9.5		
I _{IN+}	Logic "1" Input bias Current	V _{IN} = 15 V		-	30	50	μΑ	
I _{IN} _	Logic "0" Input bias Current	V _{IN} = 0 V		-	-	1	μΑ	
R _{IN}	Logic Input Pull-down Resistance			ì	500	-	kΩ	
GATE DRIV	ER OUTPUT SECTION							
V _{OH}	High-Level Output Voltage,	$I_{O} = 0 \text{ A}$ $T_{J} = 25^{\circ}\text{C}$	T _J = 25°C	-	-	1.2	V	
	V _{BIAS} -V _O		$T_J = -40^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	-	-	1.4		
V _{OL}	Low-Level Output Voltage, VO	I _O = 0 A		-	_	0.1	٧	
I _{O+}	Output HIGH Short-Circuit Pulse Current (Note 8)	$V_0 = 0 \text{ V}, V_{IN} = 5 \text{ V} \text{ with PW} \le 10 \mu\text{s}$		-	2.0	-	Α	

Table 4. STATIC ELECTRICAL CHARACTERISTICS $(V_{BIAS}(V_{CC}, V_{BS}, V_{DD}) = 15.0 \text{ V}$, $T_J = -40^{\circ}\text{C}$ to 125°C , unless otherwise specified. The V_{IH} , V_{IL} and I_{IN} parameters are referenced to V_{SS} and are applicable to respective input leads: HIN, LIN and SD. The V_O and I_O parameters are referenced to V_S and COM and are applicable to the respective output leads: HO and LO. The V_{DDUV} parameters are referenced to COM. The V_{BSUV} parameters are referenced to $V_{S1, 2, 3}$ (continued)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
GATE DRIV	ER OUTPUT SECTION					
I _{O-}	Output LOW Short-Circuit Pulsed Current (Note 8)	$V_O = 15$ V, $V_{IN} = 0$ V with PW $\leq 10~\mu s$	-	3.0	-	Α
V _S	Allowable Negative V _S Pin Voltage for HIN Signal Propagation to HO		-	-9.8	-7.0	V

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

Table 5. DYNAMIC ELECTRICAL CHARACTERISTICS $(V_{BIAS}(V_{CC}, V_{BS}, V_{DD}) = 15.0 \text{ V}, V_S = V_{SS} = COM, C_L = 1000 \text{ pF} \text{ and } T_J = -40 \text{ 5C to } 125 \text{ 5C}, \text{ unless otherwise specified.})$

Symbol	Parameter	Conditions		Min	Тур	Max	Units
LOW-SIDE	LOW-SIDE POWER SUPPLY SECTION						
t _{ON}	Turn-On Propagation Delay	V _S = 0 V		-	500	_	ns
t _{OFF}	Turn-Off Propagation Delay	V _S = 0 V		-	550	-	ns
t _{FLTIN}	Input Filtering Time (HIN, LIN)	T _J = 25°C		80	150	220	ns
	(Note 9)	$T_J = -40^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$		80	150	300	
t _{FLTSD}	Input Filtering Time (SD)			-	30	-	ns
t _{SD}	Shutdown Propagation Delay Time	T _J = 25°C		260	330	400	ns
		T _J = -40°C to 125°C		200	330	550	
t _R	Turn-On Rise Time			-	25	-	ns
t _F	Turn-Off Fall Time				15	-	
MT	Delay Matching ,	T _J = 25°C		-	-	50	ns
	HO & LO Turn-On/OFF (Note 10)	T _J = -40°C to 125°C		-	_	60	
PM	Output Pulse–Width Matching	PW _{IN} > 1 μs	T _J = 25°C	-	50	100	ns
	(Note 11)		$T_{J} = -40^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	-	50	140	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

^{8.} These parameters are guaranteed by design.

^{9.} The minimum width of the input pulse should exceed 500 ns to ensure the filtering time of the input filter is exceeded.

^{10.} MT is defined as an absolute value of matching delay time between High-side and Low-Side.

^{11.} PM is defined as an absolute value of matching pulse-width between input and Output.

TYPICAL CHARACTERISTICS

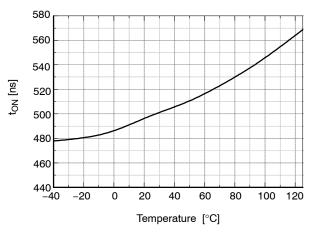


Figure 4. Turn-On Propagation Delay vs. Temperature

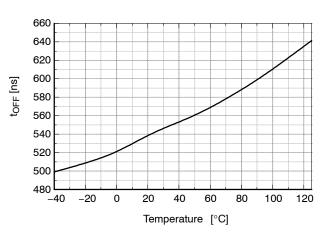


Figure 5. Turn-Off Propagation Delay vs. Temperature

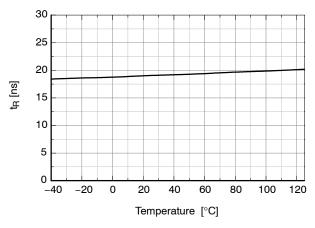


Figure 6. Turn-On Rise Time vs Temperature

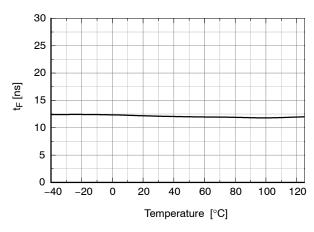


Figure 7. Turn-Off Fall Time vs. Temperature

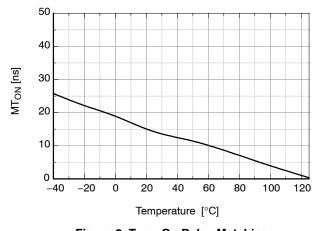


Figure 8. Turn-On Delay Matching vs. Temperature

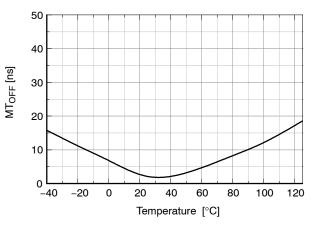


Figure 9. Turn-Off Delay Matching vs. Temperature

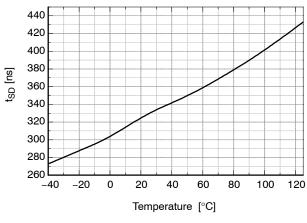


Figure 10. Shutdown Propagation Delay vs. Temperature

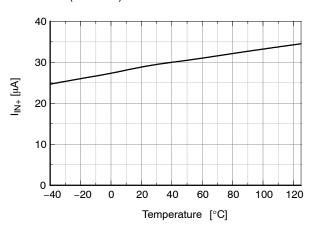


Figure 11. Logic Input High Bias Current vs. Temperature

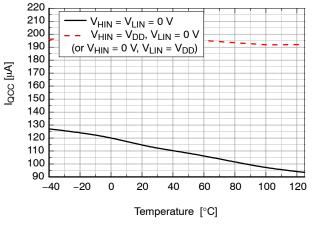


Figure 12. Quiescent V_{CC} Supply Current

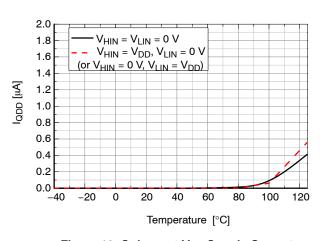


Figure 13. Quiescent V_{DD} Supply Current vs. Temperature

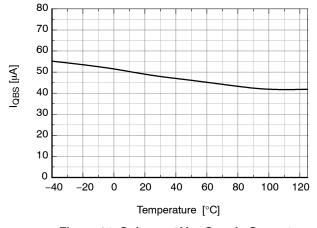


Figure 14. Quiescent V_{BS} Supply Current

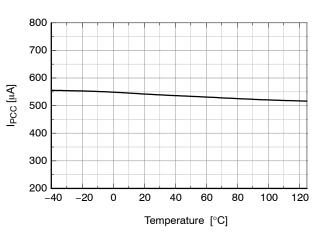


Figure 15. Operating V_{CC} Supply Current

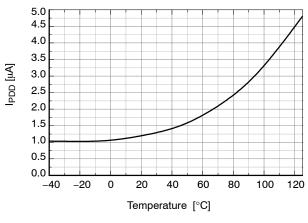


Figure 16. Operating V_{DD} Supply Current

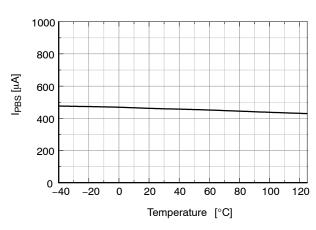


Figure 17. Operating V_{BS} Supply Current vs. Temperature

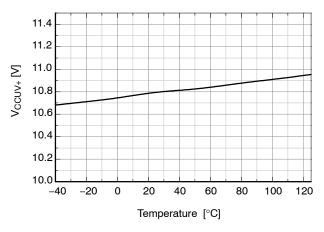


Figure 18. V_{CC} UVLO+ vs Temperature

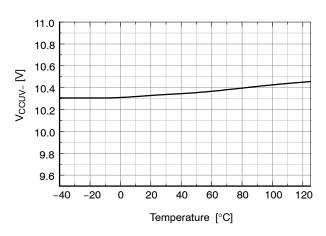


Figure 19. V_{CC} UVLO- vs. Temperature

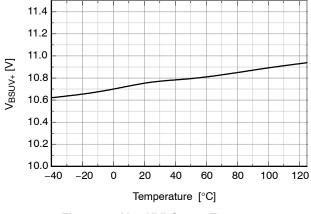


Figure 20. V_{BS} UVLO+ vs. Temperature

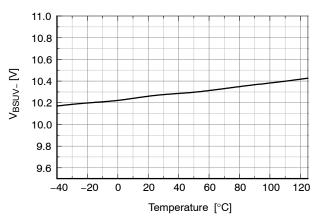


Figure 21. V_{BS} UVLO- vs. Temperature

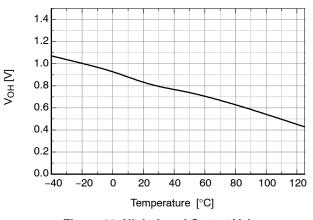


Figure 22. High-Level Output Voltage

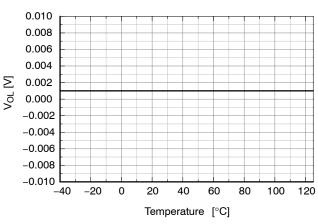


Figure 23. Low-Level Output Voltage vs. Temperature

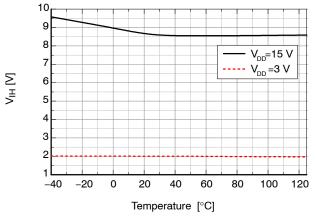


Figure 24. Logic High Input Voltage

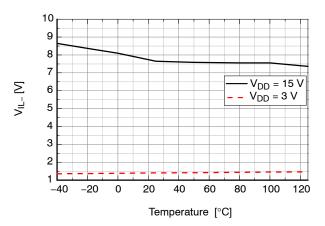


Figure 25. Logic Low Input Voltage vs. Temperature

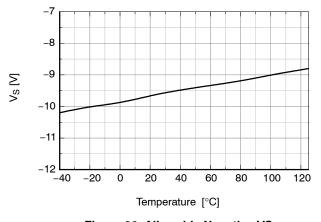


Figure 26. Allowable Negative VS vs. Temperature

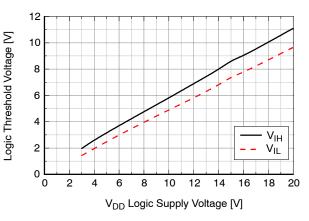


Figure 27. Input Logic (HIN&LIN) Threshold vs. V_{DD} Supply Voltage

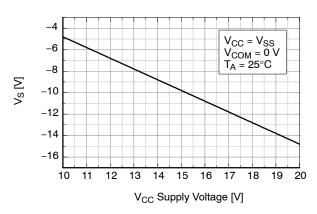


Figure 28. Allowable Negative V_S Voltage for HIN Signal Propagation to High Side vs. V_{CC} Supply Voltage

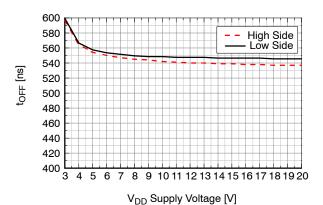


Figure 30. Turn-Off Propagation Delay vs. V_{DD} Supply Voltage

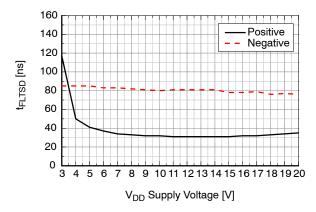


Figure 32. Shutdown Input Filtering Time vs. V_{DD} Supply Voltage

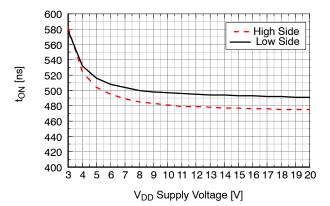


Figure 29. Turn-On Propagation Delay vs. V_{DD} Supply Voltage

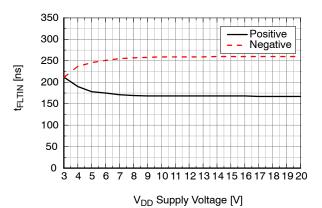


Figure 31. Logic Input Filtering Time vs. V_{DD} Supply Voltage

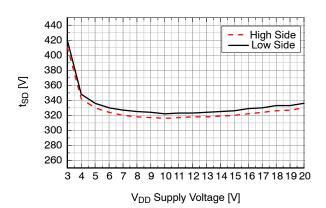


Figure 33. Shutdown Propagation Delay vs. V_{DD} Supply Voltage

TYPICAL CHARACTERISTICS (continued)

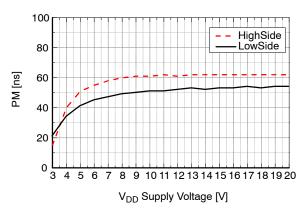


Figure 34. Output Pulse-Width Matching vs. $V_{\rm DD}$ Supply Voltage

SWITCHING TIME DEFINITIONS

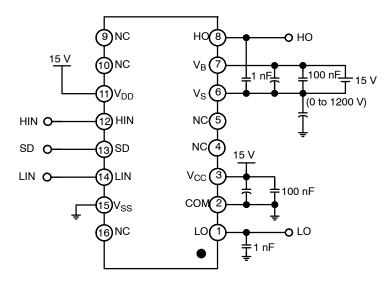


Figure 35. Switching Time Test Circuit

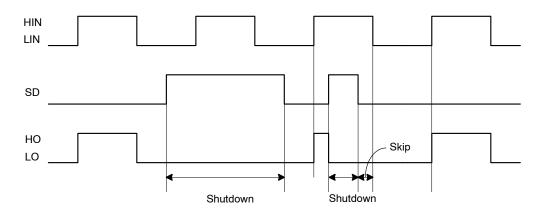


Figure 36. Input/Output Timing Diagram

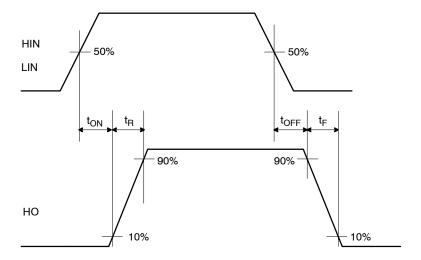


Figure 37. Switching Time Definition

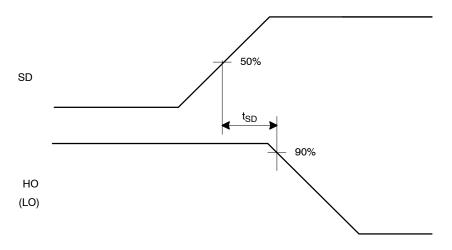


Figure 38. Shutdown Waveform Definition

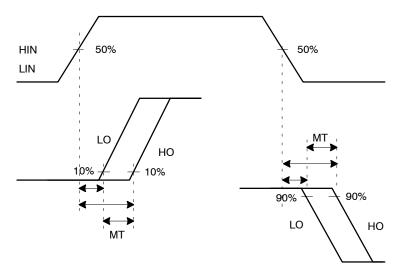


Figure 39. Delay Matching Waveform Definitions

APPLICATIONS INFORMATION

Shutdown Input

When the SD pin is in LOW state, the gate driver operates normally. When a condition occurs that should shut down the gate driver, the SD pin should be HIGH. The Shutdown circuitry has an input filter; the minimum input duration is specified by $t_{\rm FLTIN}$ (typically 250 ns).

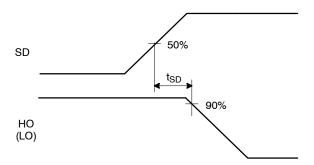


Figure 40. Output Shutdown Timing Waveform

Noise Filter

Input Noise Filter

Figure 41 shows the input noise filter method, which has symmetry duration between the input signal (t_{INPUT}) and the output signal (t_{OUTPUT}) and helps to reject noise spikes and short pulses. This input filter is applied to the HIN, LIN, and EN inputs. The upper pair of waveforms (Example A) shows an input signal duration (t_{INPUT}) much longer than input filter time (t_{FLTIN}); it is approximately the same duration between the input signal time (t_{INPUT}) and the output signal time (t_{OUTPUT}). The lower pair of waveforms (Example B) shows an input signal time (t_{INPUT}) slightly longer than input filter time (t_{FLTIN}); it is approximately the same duration between input signal time (t_{INPUT}) and the output signal time (t_{OUTPUT}).

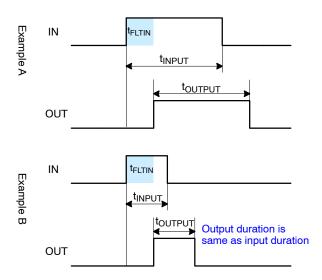


Figure 41. Input Noise Filter Definition

Short-Pulsed Input Noise Rejection Method

The input filter circuitry provides protection against short-pulsed input signals (HIN, LIN, and SD) on the input signal lines by applied noise signal.

If the input signal duration is less than input filter time (t_{FLTIN}) , the output does not change states.

Example A and B of the Figure 42 show the input and output waveforms with short-pulsed noise spikes with a duration less than input filter time; the output does not change states.

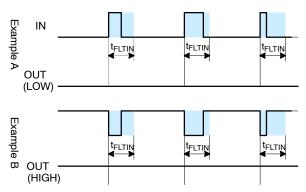


Figure 42. Noise Rejecting Input Filter Definition

Negative VS Transient

The bootstrap circuit has the advantage of being simple and low cost, but has some limitations. The biggest difficulty with this circuit is the negative voltage present at the emitter of the high-side switching device when high-side switch is turned-off in half-bridge application. If the high-side switch, Q1, turns-off while the load current is flowing to an inductive load, a current commutation occurs from high-side switch, Q1, to the diode, D2, in parallel with the low-side switch of the same inverter leg. Then the negative voltage present at the emitter of the high-side switching device, just before the freewheeling diode, D2, starts clamping, causes load current to suddenly flow to the low-side freewheeling diode, D2, as shown in Figure 43.

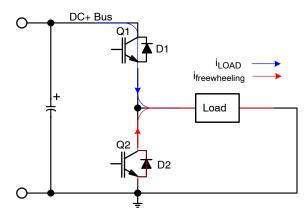


Figure 43. Half-Bridge Application Circuits

This negative voltage can be trouble for the gate driver's output stage, there is the possibility to develop an over-voltage condition of the bootstrap capacitor, input signal missing and latch-up problems because it directly affects the source VS pin of the gate driver, shown in Figure 44. This undershoot voltage is called "negative VS transient".

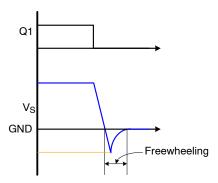


Figure 44. V_S Waveforms During Q1 Turn-Off

Figure 45 and Figure 46 show the commutation of the load current between high-side switch, Q1, and low-side freewheeling diode, D3, in same inverter leg. The parasitic inductances in the inverter circuit from the die wire bonding to the PCB tracks are jumped together in LC and LE for each IGBT. When the high-side switch, Q1, and low-side switch, Q4, are turned on, the VS1 node is below DC+ voltage by the voltage drops associated with the power switch and the parasitic inductances of the circuit due to load current is flows from O1 and O4, as shown in Figure 45. When thehigh-side switch, Q1, is turned off and Q4, remained turned on, the load current to flows the low-side freewheeling diode, D3, due to the inductive load connected to VS1 as shown in Figure 46. Q1 Turn-Off and D3 Conducting. The current flows from ground (which is connected to the COM pin of the gate driver) to the load and the negative voltage present at the emitter of the high-side switching device. In this case, the COM pin of the gate driver is at a higher potential than the V_S pin due to the voltage drops associated with freewheeling diode, D3, and parasitic elements, L_{C3} and L_{E3}.

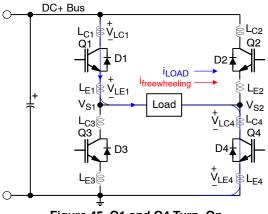


Figure 45. Q1 and Q4 Turn-On

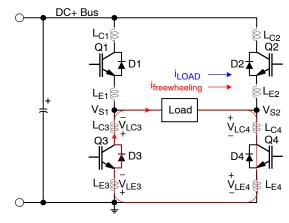


Figure 46. Q1 Turn-Off and D3 Conducting

The FAN73912A has a typical negative V_S transient characteristics, as shown in Figure 47.



Figure 47. Negative V_S Transient Characteristic

Even though the FAN73912A has been shown able to handle these negative V_S transient conditions, it is strongly recommended that the circuit designer limit the negative V_S transient as much as possible by careful PCB layout to minimize the value of parasitic elements and component use. The amplitude of negative V_S voltage is proportional to the parasitic inductances and the turn–off speed, di/dt, of the switching device.

General Guidelines

Printed Circuit Board Layout

The layout recommended for minimized parasitic elements is as follows:

- Direct tracks between switches with no loops or deviation.
- Avoid interconnect links. These can add significant inductance.
- Reduce the effect of lead-inductance by lowering package height above the PCB.
- Consider co-locating both power switches to reduce track length.

- To minimize noise coupling, the ground plane should not be placed under or near the high-voltage floating side.
- To reduce the EM coupling and improve the power switch turn-on/off performance, the gate drive loops must be reduced as much as possible.

Placement of Components

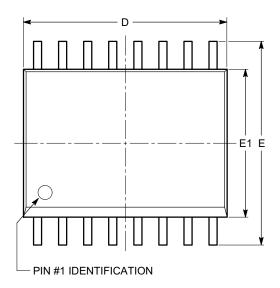
The recommended placement and selection of component as follows:

- Place a bypass capacitor between the V_{CC} and V_{SS} pins. A ceramic 1 μF capacitor is suitable for most applications. This component should be placed as close as possible to the pins to reduce parasitic elements.
- The bypass capacitor from V_{CC} to V_{SS} supports both the low-side driver and bootstrap capacitor recharge.
 A value at least ten times higher than the bootstrap capacitor is recommended.
- The bootstrap resistor, R_{BOOT}, must be considered in sizing the bootstrap resistance and the current developed during initial bootstrap charge. If the resistor is needed in series with the bootstrap diode, verify that V_B does not fall below COM (ground). Recommended

- use is typically $5 \sim 10~\Omega$ that increase the V_{BS} time constant. If the voltage drop of bootstrap resistor and diode is too high or the circuit topology does not allow a sufficient charging time, a fast recovery or ultra–fast recovery diode can be used.
- The bootstrap capacitor, C_{BOOT}, uses a low-ESR capacitor, such as ceramic capacitor. It is strongly recommended that the placement of components is as follows:
- Place components tied to the floating voltage pins (V_B and V_S) near the respective high-voltage portions of the device and the FAN73912A. Not Connected (NC) pins in this package maximize the distance between the high-voltage and low-voltage pins (see Figure 3).
- Place and route for bypass capacitors and gate resistors as close as possible to gate drive IC.
- Locate the bootstrap diode, D_{BOOT}, as close as possible to bootstrap capacitor, C_{BOOT}.
- The bootstrap diode must use a lower forward voltage drop and minimal switching time as soon as possible for fast recovery or ultra-fast diode.

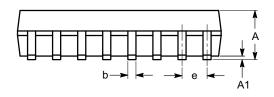
PACKAGE DIMENSIONS

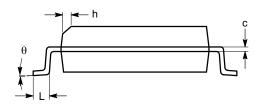
SOIC-16, 300 mils CASE 751BH-01 ISSUE A



SYMBOL	MIN	NOM	MAX
Α	2.36	2.49	2.64
A1	0.10		0.30
b	0.33	0.41	0.51
С	0.18	0.23	0.28
D	10.08	10.31	10.49
E	10.01	10.31	10.64
E1	7.39	7.49	7.59
е		1.27 BSC	
h	0.25		0.75
L	0.38	0.81	1.27
θ	0°		8°

TOP VIEW





SIDE VIEW

END VIEW

Notes:

- (1) All dimensions are in millimeters. Angles in degrees.
- (2) Complies with JEDEC MS-013.

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